

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/537,189	WEN ET AL.
	Examiner	Art Unit
	Shih-Chao Chen	2821

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	700MS	7/24/2006	CHEN
343	770	7/24/2006	CHEN